

SUPPLEMENTARY MATERIALS

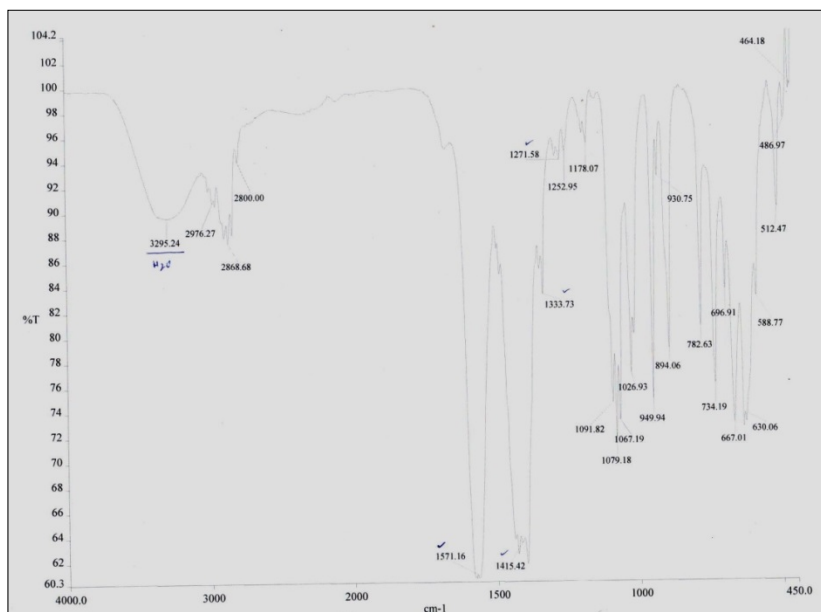


Fig. S1. FT-IR of precursor 1

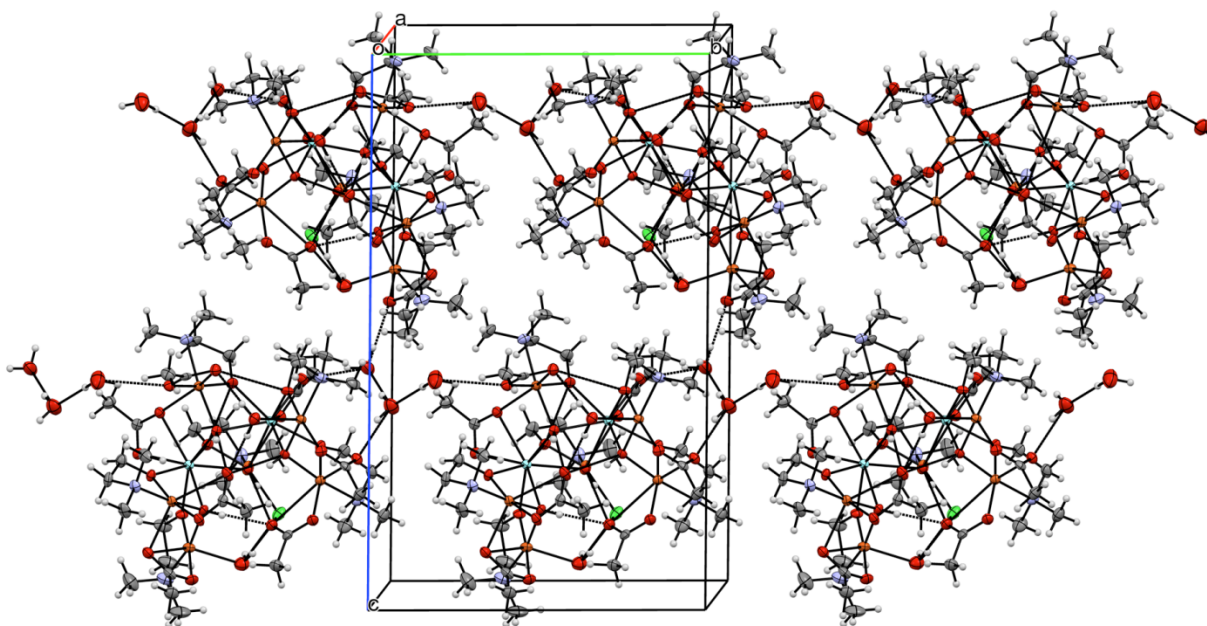


Fig S2a. Molecules of the Y-Cu complex, connected via hydrogen bonding to water solvent clusters (H₂O)₃ into a two-dimensional network parallel to the (bc) plane

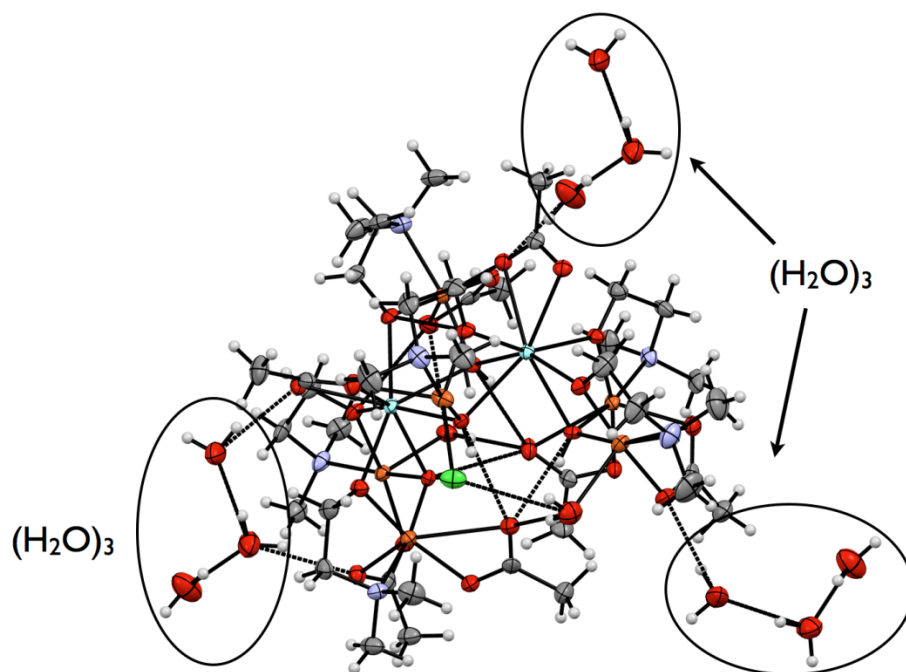


Fig. S2b. Representation of (H₂O)₃ water clusters attached to one molecule of the Y-Cu complex.

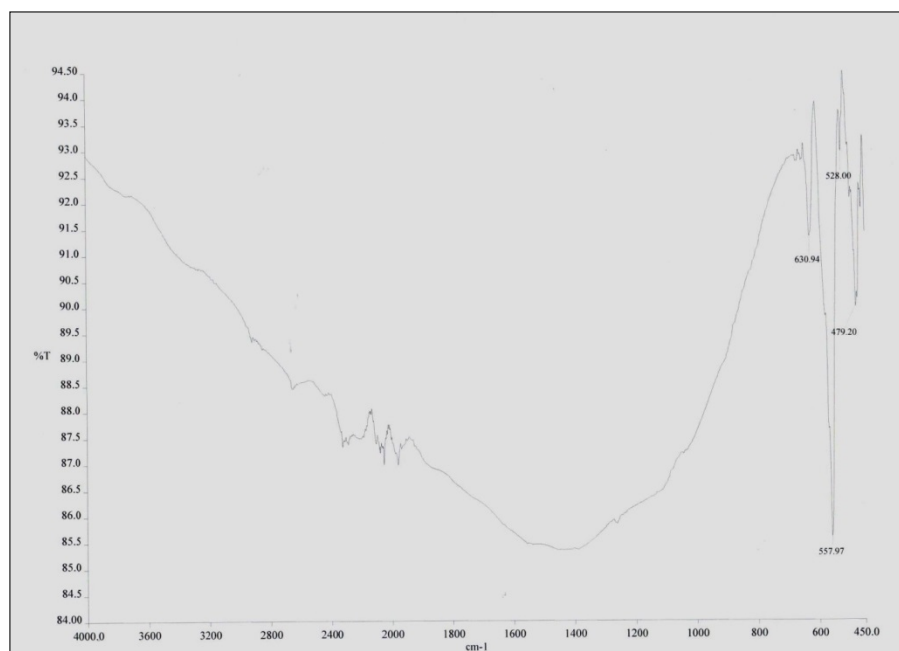


Fig. S3a. FT-IR of residue of decomposed precursor **1** under oxygen ambient.

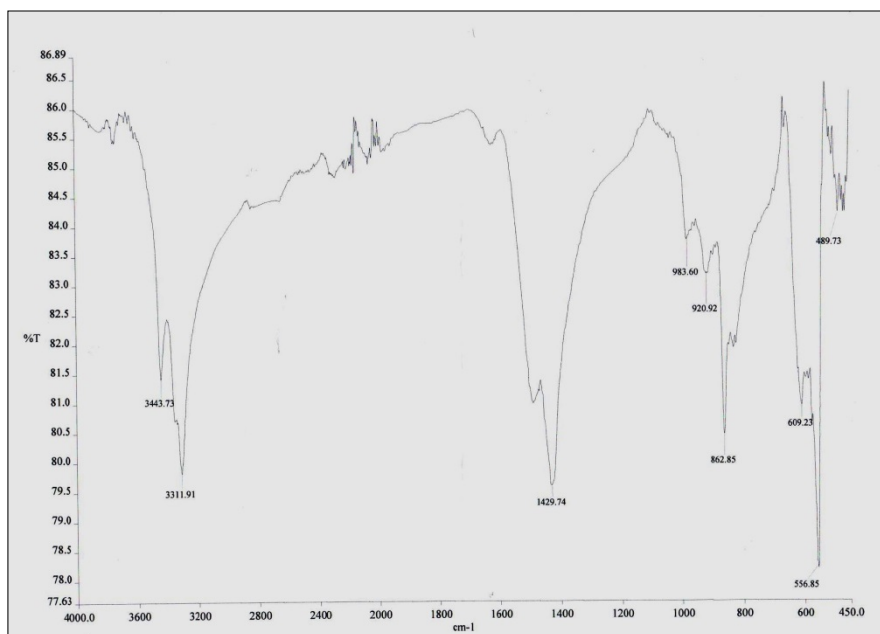


Fig. S3b. FT-IR of residue of decomposed precursor **1** under nitrogen ambient.

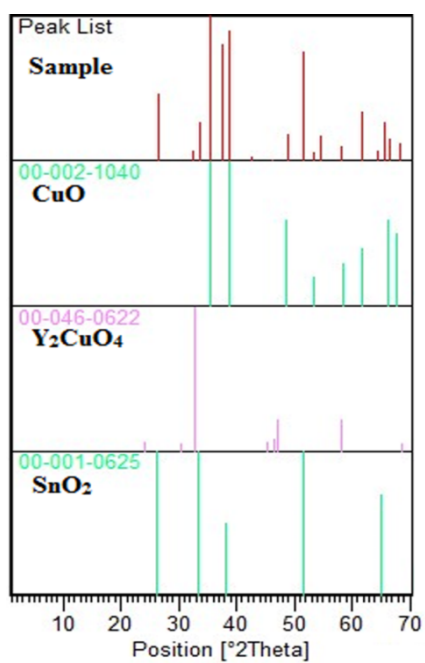


Fig. S4. Stick pattern matching of XRD of Y₂CuO₄-5CuO thin film with the standard ICDD pattern of CuO, Y₂CuO₄ and SnO₂ respectively.

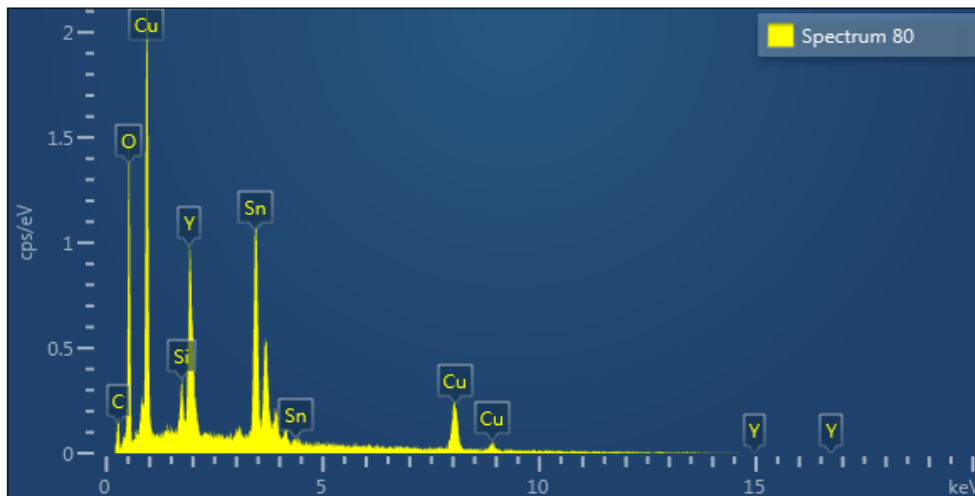


Fig. S5a. Large area scanned EDX of thin films formed from toluene.

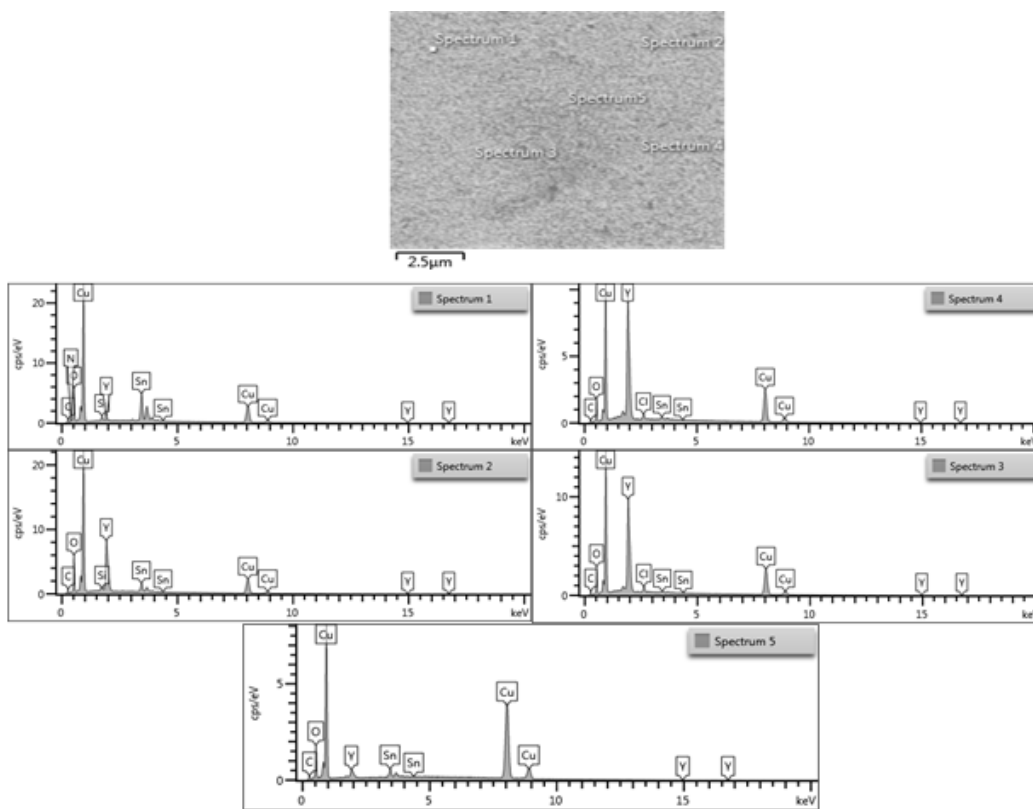


Fig. S5b. Spot EDX analysis of $\text{Y}_2\text{CuO}_4\text{-5CuO}$ composite thin films at five different places.

Table S1. Metal-Metal distances (Å) for **1**

Y(1)-Y(2)	3.8342(7)
Y(1)-Cu(1)	3.3925(8)
Y(1)-Cu(2)	3.3497(7)
Y(1)-Cu(3)	3.5611(7)
Y(1)-Cu(6)	3.3093(7)
Y(2)-Cu(3)	3.3616(7)
Y(2)-Cu(4)	3.4143(7)
Y(2)-Cu(5)	3.3479(7)
Y(2)-Cu(6)	3.6182(7)
